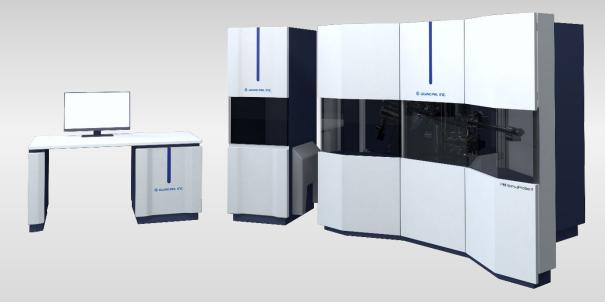
Scanning XPS Microprobe

Legacy X Innovation = Future PHI VersaProbe 4



Improved spectroscopic performance

- High sensitivity in small and large area analysis using micro-focused, scanning X-ray source

New! Large area imaging and mapping

- Improved stage-driven Scanned X-ray Imaging (SXI) for large area sample navigation
- Added features for large area chemical maps and overlays

High performance depth profiling

- Multiple ion gun options for a variety of organic, inorganic, and mixed materials
- Advanced software for thin film structure analysis

Reliable automation and remote operation

- Highly configurable queuing system for automated analysis and maximum efficiency
- Fully remote operation and advanced remote diagnostics

Environmentally friendly modern configuration

- Efficient power consumption, faster pump-down and ergonomic design

